

Special Issue

Advances in Risk and Reliability Analysis

Message from the Guest Editor

The main objective of this Special Issue is to help reliability analysts/engineers/managers/practitioners to analyze the failure behavior of a system more consistently and logically. To this effect, methodological and structured frameworks should make use of both qualitative and quantitative techniques for risk, reliability, and vulnerability analysis of the system. For the quantitative framework, various artificial intelligence techniques and expert judgment methods, e.g., Bayesian networks, long short-term memory networks, failure mode and effect analysis, fuzzy and Grey relational analysis, and the success likelihood index method, have been presented to measure the failure rate or risk metric of the system. Several versions of these methods have evolved considering varying dynamics, fuzzy, and processes of a system when evaluating the risk and reliability.

Guest Editor

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Deadline for manuscript submissions

31 January 2025



Applied Sciences

an Open Access Journal
by MDPI

Impact Factor 2.5
CiteScore 5.3



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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